

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Aaron PARTRIDGE et al.
Serial No. : 10/713,172
Filing Date : November 14, 2003
For : CRACK AND RESIDUE FREE CONFORMAL
DEPOSITED SILICON OXIDE WITH
PREDICTABLE AND UNIFORM ETCHING
CHARACTERISTICS
Examiner : Francis P. Smith
Group Art Unit : 1792
Confirmation No. : 9823
Customer No. : 26646

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I hereby certify that this correspondence is being
electronically transmitted to the United States Patent and
Trademark Office via the Office electronic filing system on
February 17, 2009.

Signature: /Aaron Grunberger/
Aaron Grunberger (Reg. No. 59,210)

AMENDMENT AFTER FINAL OFFICE ACTION

SIR:

In response to the Final Office Action of November 7, 2008, please reconsider
the above-identified application based on the following.

Amendments to the Claims are reflected in the listing of the claims which
begins on page 2 of this paper.

Remarks begin on page 10 of this paper.